

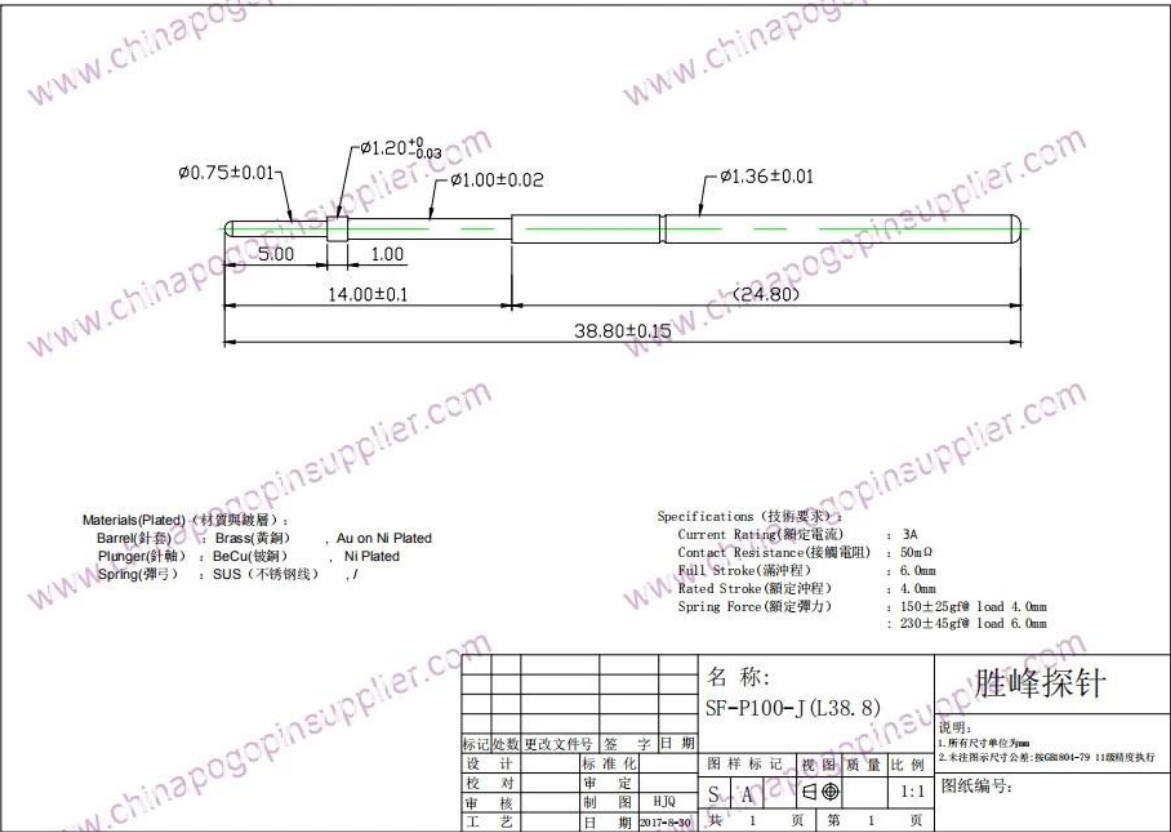
ICT 测试 测试 SF-PA100-J L38.8

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Spring loaded pin (single) for PCB, ICT, FCT testing etc;

Pogo pin (connector) to establish connection between two printed circuit boards for charging, locating, Battery, Semiconductor & Interconnect applications;

Double ended probe for BGA and Semiconductor testing;

Universal pin without spring, coating pin, LM pin with QZ and VZ series;

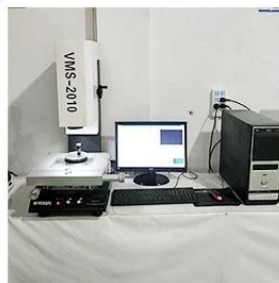
High current probe, Switch probe, Capacitance needle;

Terminal & receptacle /socket;

Other related electronic components, 30# OK wire, Jig locks, POM, Iron hinge etc



1. Agilent current testing



2. Quadratic element



3. Load Curve Meter



4. Bond Test



5. Life Fatigue Test



6. Microscope



Standard products will be delivered out within 3 days. Customized products will be sent out within 15 days.

